

SN5400, SN54LS00, SN54S00, SN7400, SN74LS00, SN74S00 QUADRUPLE 2-INPUT POSITIVE-NAND GATES

DECEMBER 1983—REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

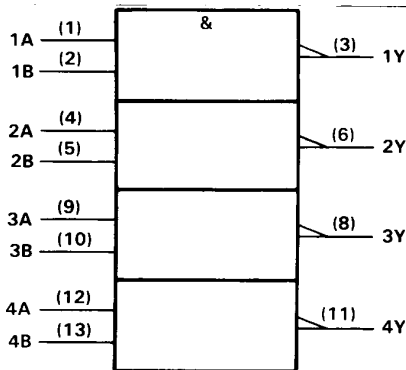
These devices contain four independent 2-input-NAND gates.

The SN5400, SN54LS00, and SN54S00 are characterized for operation over the full military temperature range of -55°C to 125°C . The SN7400, SN74LS00, and SN74S00 are characterized for operation from 0°C to 70°C .

FUNCTION TABLE (each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

logic symbol†

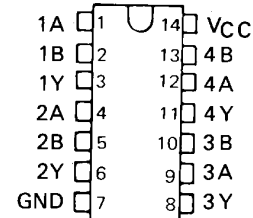


†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

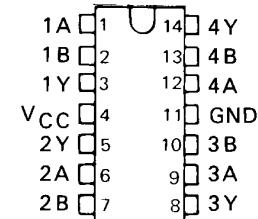
Pin numbers shown are for D, J, and N packages.

SN5400 . . . J PACKAGE
SN54LS00, SN54S00 . . . J OR W PACKAGE
SN7400 . . . N PACKAGE
SN74LS00, SN74S00 . . . D OR N PACKAGE

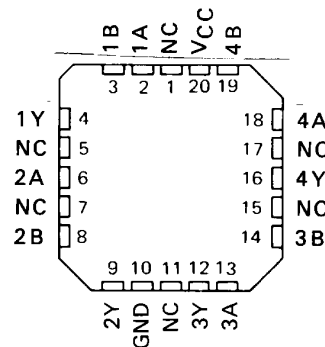
(TOP VIEW)



SN5400 . . . W PACKAGE
(TOP VIEW)

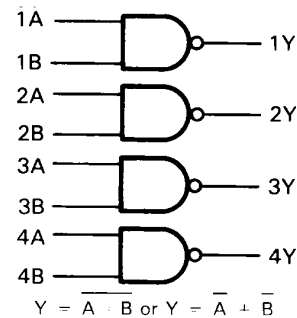


SN54LS00, SN54S00 . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

logic diagram (positive logic)



$$Y = \overline{A \cdot B} \text{ or } Y = \overline{A} + \overline{B}$$

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

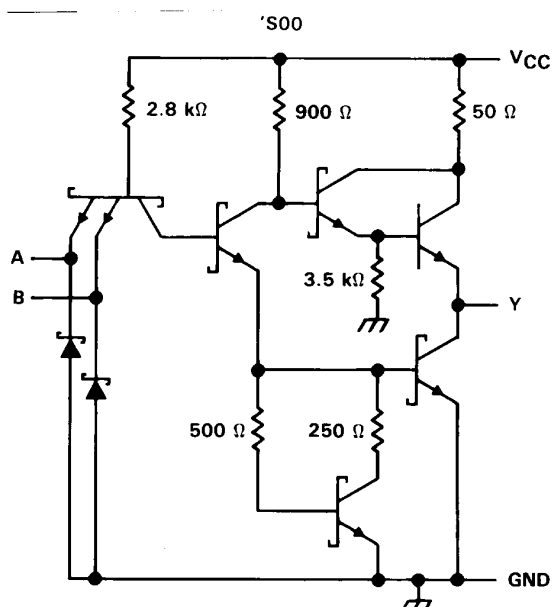
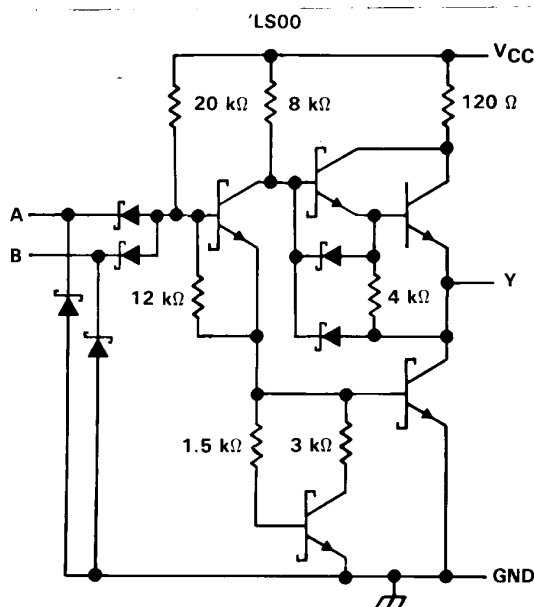
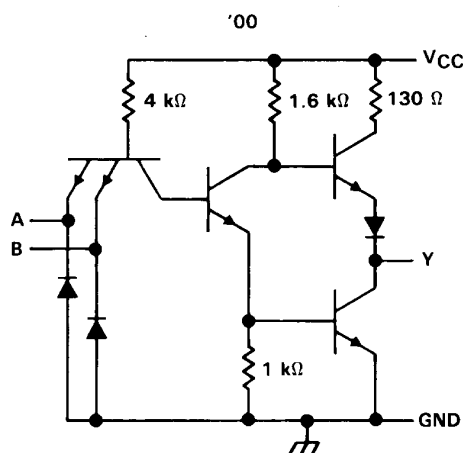
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**SN5400, SN54LS00, SN54S00,
SN7400, SN74LS00, SN74S00
QUADRUPLE 2-INPUT POSITIVE-NAND GATES**

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '00, 'S00	5.5 V
'LS00	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

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SN5400, SN7400 QUADRUPLE 2-INPUT POSITIVE-NAND GATES

recommended operating conditions

	SN5400			SN7400			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.8			0.8	V
I_{OH} High-level output current			-0.4			-0.4	mA
I_{OL} Low-level output current			16			16	mA
T_A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN5400			SN7400			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V_{IK}	$V_{CC} = \text{MIN}, I_I = -12 \text{ mA}$			-1.5			-1.5	V
V_{OH}	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -0.4 \text{ mA}$	2.4	3.4		2.4	3.4		V
V_{OL}	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 16 \text{ mA}$		0.2	0.4		0.2	0.4	V
I_I	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1	mA
I_{IH}	$V_{CC} = \text{MAX}, V_I = 2.4 \text{ V}$			40			40	µA
I_{IL}	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$			-1.6			-1.6	mA
$I_{OS} §$	$V_{CC} = \text{MAX}$	-20		-55	-18		-55	mA
I_{CCH}	$V_{CC} = \text{MAX}, V_I = 0 \text{ V}$		4	8		4	8	mA
I_{CCL}	$V_{CC} = \text{MAX}, V_I = 4.5 \text{ V}$		12	22		12	22	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$.

§ Not more than one output should be shorted at a time.

switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	A or B	Y	$R_L = 400 \Omega, C_L = 15 \text{ pF}$		11	22	ns
t_{PHL}					7	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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SN54S00, SN74S00 **QUADRUPLE 2-INPUT POSITIVE-NAND GATES**

recommended operating conditions

	SN54S00			SN74S00			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			− 1			− 1	mA
I _{OL} Low-level output current			20			20	mA
T _A Operating free-air temperature	− 55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54S00			SN74S00			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = −18 mA			−1.2			−1.2	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = −1 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 20 mA			0.5			0.5	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			50			50	μA
I _{IL}	V _{CC} = MAX, V _I = 0.5 V			−2			−2	mA
I _{OS} §	V _{CC} = MAX	−40		−100	−40		−100	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		10	16		10	16	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		20	36		20	36	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A or B	Y	R _L = 280 Ω, C _L = 15 pF		3	4.5	ns
t _{PHL}					3	5	ns
t _{PLH}			R _L = 280 Ω, C _L = 50 pF		4.5		ns
t _{PHL}					5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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